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Search Results - Record(s) 1 through 4 of 4 returned.

☑ 1. Document ID: US 5493729 A

Using default format because multiple data bases are involved.

L15: Entry 1 of 4

File: USPT

Feb 20, 1996

US-PAT-NO: 5493729

DOCUMENT-IDENTIFIER: US 5493729 A

TITLE: Knowledge data base processing system and expert system

DATE-ISSUED: February 20, 1996

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Nigawara; Seiitsu Hitachi JP
Namba; Shigeaki Hitachi JP
Kohmoto; Hiroshi Hitachi JP

US-CL-CURRENT: 706/52; 706/60



☑ 2. Document ID: US 5005143 A

L15: Entry 2 of 4 File: USPT Apr 2, 1991

US-PAT-NO: 5005143

DOCUMENT-IDENTIFIER: US 5005143 A

TITLE: Interactive statistical system and method for predicting expert decisions

DATE-ISSUED: April 2, 1991

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Altschuler; Martin D. Wallingford PA Whittington; Richard Media PA

US-CL-CURRENT: 702/181; 706/46, 706/52, 706/924

Record List Display Page 2 of 3

Full Title Citation Front Review Classification Date Reference

☐ 3. Document ID: DE 4108310 A, JP 3268529 B2, US 5493729 A, DE 4108310 C2

L15: Entry 3 of 4

File: DWPI

Sep 26, 1991

DERWENT-ACC-NO: 1991-289202

DERWENT-WEEK: 200222

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TITLE: Knowledge base processing and expert system - stores indices representing certainty grade of casual relationship between occurrence and others relevant to it

INVENTOR: KOHMOTO, H; NAMBA, S; NIGAWARA, S

PRIORITY-DATA: 1990JP-0063697 (March 14, 1990)

PATENT-FAMILY:

PUB-NO	PUB-DATE	LANGUAGE	PAGES	MAIN-IPC
DE 4108310 A	September 26, 1991		000	
JP 3268529 B2	March 25, 2002		019	G06F009/44
US 5493729 A	February 20, 1996		023	G06F015/18
DE 4108310 C2	October 22, 1998		000	G06F015/18

INT-CL (IPC): G06F 9/44; G06F 15/18

Full	Title	Citation	Front	Review	Classification	Date	Reference	L. Initia	Claims	KWIC	Draw, De

☐ 4. Document ID: US 5005143 A

L15: Entry 4 of 4

File: DWPI

Apr 2, 1991

DERWENT-ACC-NO: 1991-117187

DERWENT-WEEK: 199116

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TITLE: Interactive statistical system and predicting expert decisions - repeating random value generation and corresponding responses until sufficient are given to

achieve set statistical significance

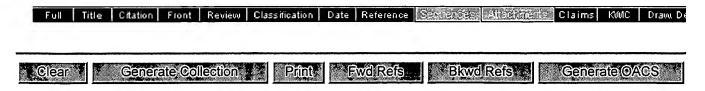
PRIORITY-DATA: 1989US-0411911 (September 25, 1989), 1987US-0065304 (June 19, 1987)

PATENT-FAMILY:

PUB-NO PUB-DATE LANGUAGE PAGES MAIN-IPC

US 5005143 A April 2, 1991 000

INT-CL (IPC): G06F 9/00; G06F 15/42



Terms	Documents
(5,005,143 5,493,729).pn.	4

Display Format: - Change Format

Previous Page Next Page Go to Doc#

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(5,005,143 5,493,729).pn.	4

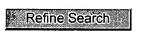
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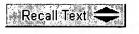
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Derwent World Patents Index
IBM Technical Disclosure Bulletins

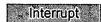
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<u>L14</u>	L13 and troubleshoot\$4	16	<u>L14</u>
<u>L13</u>	L12 and bayesian	63	<u>L13</u>
<u>L12</u>	diagnostic adj systems	3451	<u>L12</u>
<u>L11</u>	L10 and sequence and resolution	7	<u>L11</u>
<u>L10</u>	diagnostic adj model	85	<u>L10</u>
<u>L9</u>	probabil\$6 and troubleshooters and diagnostics	2	<u>L9</u>
<u>L8</u>	L4 and probabil\$6 and troubleshoot and diagnostics	3	<u>L8</u>
<u>L7</u>	L4 and probabil\$6 and debug and diagnos\$6	9	<u>L7</u>
<u>L6</u>	L4 and probabil\$6 and diagnos\$6	54	<u>L6</u>
<u>L5</u>	L4 and probabil\$6 and troubleshooters and diagnostics	0	<u>L5</u>
<u>L4</u>	706/52.ccls.	393	<u>L4</u>
<u>L3</u>	6,456,622.pn.	2	<u>L3</u>
<u>L2</u>	4,866,635.pn.	2	<u>L2</u>

<u>L1</u> 6,535,865.pn.

2 <u>L1</u>

END OF SEARCH HISTORY

Record List Display Page 1 of 2

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Search Results - Record(s) 1 through 2 of 2 returned.

☐ 1. Document ID: US 5133046 A

Using default format because multiple data bases are involved.

L16: Entry 1 of 2

File: USPT

Jul 21, 1992

US-PAT-NO: 5133046

DOCUMENT-IDENTIFIER: US 5133046 A

TITLE: Computer-based diagnostic expert system organized according to Bayesian

theory

DATE-ISSUED: July 21, 1992

INVENTOR-INFORMATION:

NAME CITY

STATE ZIP CODE COUNTRY

Kaplan; Stanley

Rancho Palas Verdes

CA

US-CL-CURRENT: 706/52; 706/912, 706/914

Full Title Citation Front Review Classification Date Reference Sequences Attack ments. Claims KMC Draw De

2. Document ID: US 5133046 A

L16: Entry 2 of 2

File: DWPI

Jul 21, 1992

DERWENT-ACC-NO: 1992-268277

DERWENT-WEEK: 199232

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TITLE: Computer-based diagnostic expert system organised according to bayesian theory - generates diagnosis in form of probability distributions, responding to

evidence in discrete time trajectories and data from knowledge base

INVENTOR: KAPLAN, S

PRIORITY-DATA: 1991US-0637190 (January 3, 1991)

PATENT-FAMILY:

PUB-NO PUB-DATE LANGUAGE

PAGES MAIN-IPC

US 5133046 A

July 21, 1992

022

G06F015/18

INT-CL (IPC): G06F 15/18

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachment	Claims	KMC	Draw, De
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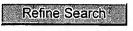
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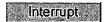
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DATE: Thursday, February 05, 2004 Printable Copy Create Case

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<u>L14</u>	L13 and troubleshoot\$4	16	<u>L14</u>
<u>L13</u>	L12 and bayesian	63	<u>L13</u>
<u>L12</u>	diagnostic adj systems	3451	<u>L12</u>
<u>L11</u>	L10 and sequence and resolution	7	<u>L11</u>
<u>L10</u>	diagnostic adj model	85	<u>L10</u>
<u>L9</u>	probabil\$6 and troubleshooters and diagnostics	2	<u>L9</u>
<u>L8</u>	L4 and probabil\$6 and troubleshoot and diagnostics	3	<u>L8</u>
<u>L7</u>	L4 and probabil\$6 and debug and diagnos\$6	9	<u>L7</u>
<u>L6</u>	L4 and probabil\$6 and diagnos\$6	54	<u>L6</u>
<u>L5</u>	L4 and probabil\$6 and troubleshooters and diagnostics	0	<u>L5</u>
<u>L4</u>	706/52.ccls.	393	<u>L4</u>
<u>L3</u>	6,456,622.pn.	2	<u>L3</u>

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1 Probabilistic relevance relations

Geiger, D.; Heckerman, D.;

Systems, Man and Cybernetics, Part A, IEEE Transactions on ,Volume: 28, I 1, Jan. 1998

Pages:17 - 25

[Abstract] [PDF Full-Text (560KB)] IEEE JNL

2 Decision-theoretic case-based reasoning

Breese, J.S.; Heckerman, D.;

Systems, Man and Cybernetics, Part A, IEEE Transactions on ,Volume: 26, I

6 , Nov. 1996 Pages: 838 - 842

[Abstract] [PDF Full-Text (552KB)] IEEE JNL

3 Causal independence for probability assessment and inference using **Bayesian networks**

Heckerman, D.; Breese, J.S.;

Systems, Man and Cybernetics, Part A, IEEE Transactions on ,Volume: 26 , I 6 , Nov. 1996

Pages:826 - 831

[Abstract] [PDF Full-Text (604KB)] IEEE JNL

4 An approximate nonmyopic computation for value of information

Heckerman, D.; Horvitz, E.; Middleton, B.;

Pattern Analysis and Machine Intelligence, IEEE Transactions on ,Volume:

15 , Issue: 3 , March 1993

Pages: 292 - 298

[Abstract] [PDF Full-Text (604KB)] IEEE JNL

5 Separating appearance from deformation

Jojic, N.; Simard, P.; Frey, B.J.; Heckerman, D.;

Computer Vision, 2001. ICCV 2001. Proceedings. Eighth IEEE International

Conference on ,Volume: 2 , 7-14 July 2001

Pages: 288 - 294 vol. 2

[Abstract] [PDF Full-Text (788KB)] IEEE CNF

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<u>L10</u>	diagnostic adj model	85	<u>L10</u>
<u>L9</u>	probabil\$6 and troubleshooters and diagnostics	2	<u>L9</u>
<u>L8</u>	L4 and probabil\$6 and troubleshoot and diagnostics	3	<u>L8</u>
<u>L7</u>	L4 and probabil\$6 and debug and diagnos\$6	9	<u>L7</u>
<u>L6</u>	L4 and probabil\$6 and diagnos\$6	54	<u>L6</u>
<u>L5</u>	L4 and probabil\$6 and troubleshooters and diagnostics	0	<u>L5</u>
<u>L4</u>	706/52.ccls.	393	<u>L4</u>
<u>L3</u>	6,456,622.pn.	2	<u>L3</u>
<u>L2</u>	4,866,635.pn.	2	<u>L2</u>
L1	6,535,865.pn.	2	L1

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Search Results - Record(s) 1 through 9 of 9 returned.

☐ 1. Document ID: US 5751915 A

Using default format because multiple data bases are involved.

L7: Entry 1 of 9

File: USPT

May 12, 1998

US-PAT-NO: 5751915

DOCUMENT-IDENTIFIER: US 5751915 A

TITLE: Elastic fuzzy logic system

DATE-ISSUED: May 12, 1998

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE

Werbos; Paul J. College Park MD 20740

US-CL-CURRENT: 706/4; 706/2, 706/52

Full Title Citation Front Review Classification Date Reference Sentence Attachments Claims KMC Draw De

☐ 2. Document ID: US 5604841 A

L7: Entry 2 of 9

File: USPT

Feb 18, 1997

COUNTRY

US-PAT-NO: 5604841

DOCUMENT-IDENTIFIER: US 5604841 A

TITLE: Hierarchical restructuring generic test templates and reusable value spaces

for machine failure isolation using qualitative physics

DATE-ISSUED: February 18, 1997

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Hamilton; Thomas P. South Windsor CT Clark; Robert T. Enfield CT Gallo; Steven Vernon CT

US-CL-CURRENT: 706/11; 706/52

Full Title Citation Front Review Classification Date Reference Sequences Attack freeing Claims KMC Draw De

☐ 3. Document ID: US 5537644 A

L7: Entry 3 of 9

File: USPT

Jul 16, 1996

US-PAT-NO: 5537644

DOCUMENT-IDENTIFIER: US 5537644 A

TITLE: Machine failure isolation in multiple machine configurations using

qualitative physics

DATE-ISSUED: July 16, 1996

INVENTOR-INFORMATION:

NAME

CITY

STATE ZIP CODE

COUNTRY

Hamilton; Thomas P.

South Windsor

CT

Clark; Robert T.

Enfield

CT

US-CL-CURRENT: 706/52; 702/33, 702/35

Full Title Citation Front Review Classification Date Reference Sociences Microsofts Claims KMC Draw. De

☐ 4. Document ID: US 5522014 A

L7: Entry 4 of 9

File: USPT

May 28, 1996

US-PAT-NO: 5522014

DOCUMENT-IDENTIFIER: US 5522014 A

** See image for Certificate of Correction **

TITLE: Intergrated qualitative/quantitative reasoning with enhanced core predictions and extended test procedures for machine failure isolation using qualitative physics

quarrous p...,sico

DATE-ISSUED: May 28, 1996

INVENTOR-INFORMATION:

NAME

CITY

STATE

ZIP CODE

COUNTRY

Clark; Robert T.

Enfield

CT

Hamilton; Thomas P.

South Windsor

CT

Gallo; Steven

Vernon

CT

US-CL-CURRENT: 706/45; 702/17, 706/52, 706/911, 706/912

Full Title Citation Front Review Classification Date Reference Sequences, Attachinents Claims KWIC Draw De

☐ 5. Document ID: US 5353381 A

L7: Entry 5 of 9

File: USPT

Oct 4, 1994

US-PAT-NO: 5353381

DOCUMENT-IDENTIFIER: US 5353381 A

TITLE: Intelligent test selection for machine failure isolation using qualitative

physics

DATE-ISSUED: October 4, 1994

INVENTOR-INFORMATION:

NAME

South Windsor

STATE ZIP CODE

COUNTRY

Hamilton; Thomas P.

Monroe

CTCT

Perveiler; Kevin J. Jacobsen; Carol E.

Shelton

CITY

CT

US-CL-CURRENT: 706/52

Full Title Citation Front Review Classification Date Reference Sequences Affectivents Claims KMC Draw De

☐ 6. Document ID: US 5216749 A

L7: Entry 6 of 9

File: USPT

Jun 1, 1993

US-PAT-NO: 5216749

DOCUMENT-IDENTIFIER: US 5216749 A

TITLE: Core predictions for qualitative physics

DATE-ISSUED: June 1, 1993

INVENTOR-INFORMATION:

NAME

CITY

STATE ZIP CODE COUNTRY

Hamilton; Thomas P.

South Windsor

US-CL-CURRENT: 706/52; 702/185, 706/911, 706/912, 706/913

Full Title Citation Front Review Classification Date Reference South 62 Attocharming Claims KMC Draw, De

☐ 7. Document ID: US 5202955 A

L7: Entry 7 of 9

File: USPT

Apr 13, 1993

US-PAT-NO: 5202955

DOCUMENT-IDENTIFIER: US 5202955 A

TITLE: Dynamic assumption ordering for qualitative physics

DATE-ISSUED: April 13, 1993

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE

COUNTRY

· Record List Display Page 4 of 5

Hamilton; Thomas P.

South Windsor

CT

Jacobsen; Carol E.

Shelton

CT

US-CL-CURRENT: 706/52; 702/185, 706/911, 706/912, 706/913

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KMC Draw De

□ 8. Document ID: US 5187773 A

L7: Entry 8 of 9

File: USPT

Feb 16, 1993

US-PAT-NO: 5187773

DOCUMENT-IDENTIFIER: US 5187773 A

** See image for Certificate of Correction **

TITLE: Machine failure isolation using qualitative physics

DATE-ISSUED: February 16, 1993

INVENTOR-INFORMATION:

CITY

STATE ZIP CODE

COUNTRY

Hamilton; Thomas P.

South Windsor

CT

Jacobsen; Carol E.

Shelton

CT

Perveiler; Kevin J.

Monroe

CT

US-CL-CURRENT: 706/52; 702/185, 706/911, 706/912

Full Title Citation Front Review Classification Date Reference Section 8 State Injents Claims KWC Draw De

☐ 9. Document ID: US 5138694 A

L7: Entry 9 of 9

File: USPT

Aug 11, 1992

US-PAT-NO: 5138694

DOCUMENT-IDENTIFIER: US 5138694 A

TITLE: Parallel processing qualitative reasoning system

DATE-ISSUED: August 11, 1992

INVENTOR-INFORMATION:

NAME CITY STATE

ZIP CODE

COUNTRY

Hamilton; Thomas P.

South Windosr

CT

US-CL-CURRENT: 706/52; 706/10

Full Title Citation Front Review Classification Date Reference Security Attachments Claims KMC Draw De

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Search Results - Record(s) 1 through 3 of 3 returned.

☐ 1. Document ID: US 5604841 A

Using default format because multiple data bases are involved.

L8: Entry 1 of 3

File: USPT

Feb 18, 1997

US-PAT-NO: 5604841

DOCUMENT-IDENTIFIER: US 5604841 A

TITLE: Hierarchical restructuring generic test templates and reusable value spaces

for machine failure isolation using qualitative physics

DATE-ISSUED: February 18, 1997

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Hamilton; Thomas P. South Windsor CT Clark; Robert T. Enfield CT

Gallo; Steven Vernon CT

US-CL-CURRENT: 706/11; 706/52



☐ 2. Document ID: US 5537644 A

L8: Entry 2 of 3

File: USPT

Jul 16, 1996

US-PAT-NO: 5537644

DOCUMENT-IDENTIFIER: US 5537644 A

TITLE: Machine failure isolation in multiple machine configurations using

qualitative physics

DATE-ISSUED: July 16, 1996

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Hamilton; Thomas P. South Windsor CT

Clark; Robert T. Enfield CT

US-CL-CURRENT: 706/52; 702/33, 702/35



☐ 3. Document ID: US 5522014 A

L8: Entry 3 of 3

File: USPT

May 28, 1996

US-PAT-NO: 5522014

DOCUMENT-IDENTIFIER: US 5522014 A

** See image for Certificate of Correction **

TITLE: Intergrated qualitative/quantitative reasoning with enhanced core predictions and extended test procedures for machine failure isolation using qualitative physics

DATE-ISSUED: May 28, 1996

INVENTOR-INFORMATION:

NAME

Clark; Robert T.

Hamilton; Thomas P.

Gallo; Steven

CITY

Enfield

South Windsor

Vernon

STATE ZIP CODE

CT

COUNTRY

CTCT

US-CL-CURRENT: 706/45; 702/17, 706/52, 706/911, 706/912

Full	Title	Citation	Front	Review	Classification	Date	Reference			Claims	KWC	Draw De
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☐ 1. Document ID: US 20020116351 A1

Using default format because multiple data bases are involved.

L9: Entry 1 of 2

File: PGPB

Aug 22, 2002

PGPUB-DOCUMENT-NUMBER: 20020116351

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020116351 A1

TITLE: Methods and structure for characterization of bayesian belief networks

PUBLICATION-DATE: August 22, 2002

INVENTOR-INFORMATION:

NAME

CITY

STATE

COUNTRY

RULE-47

Skaanning, Claus

Dronninglund

CO

DK

Wright, David W.

Fort Collins

US

US-CL-CURRENT: 706/21

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KMC Dra	Full	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw, D
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☐ 2. Document ID: US 6012152 A

L9: Entry 2 of 2

File: USPT

Jan 4, 2000

US-PAT-NO: 6012152

DOCUMENT-IDENTIFIER: US 6012152 A

** See image for <u>Certificate of Correction</u> **

TITLE: Software fault management system

DATE-ISSUED: January 4, 2000

INVENTOR-INFORMATION:

NAME CITY

1 TY

STATE ZIP CODE

COUNTRY

Douik; Samir

Sainte Anne de Bellevue

CA

Boutaba; Raouf

Montreal

CA

US-CL-CURRENT: 714/26

Full	Title	Citation	Front	Review	Classification	Date	Reference	Section	1 9 1 16	Claims	KWIC	Draw. [
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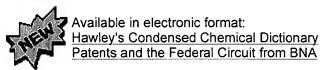
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(Citations of Defense Technical Information Center scientific and technical documents)

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A Brief History of the Hard Disk Drive

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(Full text scientific research papers - in pdf and postscript formats.)

Internet Engineering Task Force

(The IETF Secretariat, run by The Corporation for National Research Initiatives with funding from the US government, maintains an index of Internet-Drafts.)

Nanotechnology Requests for Comments (RFCs) Database

(Requests for Comments (RFC) document series is a set of technical and organizational notes about the Internet (originally the ARPANET), beginning in 1969 and discussing

many

aspects of computer networking, including protocols, procedures and concepts as well as meeting notes and opinions.)

- Usenet Archive (Google Groups)
- Wayback Machine (Archived web pages.)

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<u>L7</u>	L4 and probabil\$6 and debug and diagnos\$6	9	<u>L7</u>
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<u>L5</u>	L4 and probabil\$6 and troubleshooters and diagnostics	0	<u>L5</u>
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<u>L3</u>	6,456,622.pn.	2	<u>L3</u>
<u>L2</u>	4,866,635.pn.	2	<u>L2</u>
<u>L1</u> ·	6,535,865.pn.	2	<u>L1</u>

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Search Results - Record(s) 1 through 16 of 16 returned.

☐ 1. Document ID: US 20030167111 A1

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L14: Entry 1 of 16

File: PGPB

Sep 4, 2003

PGPUB-DOCUMENT-NUMBER: 20030167111

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20030167111 A1

TITLE: Diagnostic system and method

PUBLICATION-DATE: September 4, 2003

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY RULE-47 Kipersztok, Oscar Redmond US WA Seattle US Rein-Weston, Karl J. WA Nelson, Scott L. Issaguah WA US Dildy, Glenn A. US Sammamish WA Chew, Susan Chan Issaquah WA US

US-CL-CURRENT: 701/29; 702/185, 714/25

Full Ti	tie	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Drawi Di

☐ 2. Document ID: US 20020183988 A1

L14: Entry 2 of 16

File: PGPB

Dec 5, 2002

PGPUB-DOCUMENT-NUMBER: 20020183988

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020183988 A1

TITLE: Model selection for decision support systems

PUBLICATION-DATE: December 5, 2002

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY RULE-47

Skaanning, Claus Dronninglund CO DK Schreckengast, James Fort Collins US Record List Display Page 2 of 8

US-CL-CURRENT: 703/2

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KWC Draw. De

☐ 3. Document ID: US 20020138184 A1

L14: Entry 3 of 16

File: PGPB

Sep 26, 2002

PGPUB-DOCUMENT-NUMBER: 20020138184

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020138184 A1

TITLE: Diagnostic system and method

PUBLICATION-DATE: September 26, 2002

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY RULE-47

Kipersztok, Oscar Redmond WA US Rein-Weston, Karl J. Seattle WA US Walker, Nicholas James WA US Seattle Chew, Susan Chan US Issaquah WA

US-CL-CURRENT: 701/29; 340/945

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KWIC Draw. De

☐ 4. Document ID: US 20020116351 A1

L14: Entry 4 of 16

File: PGPB

Aug 22, 2002

PGPUB-DOCUMENT-NUMBER: 20020116351

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020116351 A1

TITLE: Methods and structure for characterization of bayesian belief networks

PUBLICATION-DATE: August 22, 2002

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY RULE-47

Skaanning, Claus Dronninglund CO DK Wright, David W. Fort Collins US

US-CL-CURRENT: 706/21

Full Title Citation Front Review Classification Date Reference Sequences Attachments Claims KWIC Draw De

Record List Display Page 3 of 8

☐ 5. Document ID: US 20020044296 A1

L14: Entry 5 of 16 File: PGPB Apr 18, 2002

PGPUB-DOCUMENT-NUMBER: 20020044296

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20020044296 A1

TITLE: Authoring tool for bayesian network diagnostic systems

PUBLICATION-DATE: April 18, 2002

INVENTOR-INFORMATION:

CITY NAME STATE COUNTRY RULE-47

Skaanning, Claus Dronninglund DK

US-CL-CURRENT: 358/1.14; 358/1.15

Full	Title	Citation Fr	ront	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw, De
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	6.	Document	ID:	US 20	010011260	A 1						

L14: Entry 6 of 16 File: PGPB Aug 2, 2001

Jul 8, 2003

PGPUB-DOCUMENT-NUMBER: 20010011260

PGPUB-FILING-TYPE: new

DOCUMENT-IDENTIFIER: US 20010011260 A1

TITLE: Automated diagnosis of printer systems using bayesian networks

PUBLICATION-DATE: August 2, 2001

INVENTOR-INFORMATION:

NAME CITY STATE COUNTRY RULE-47 Dronninglund DK Skaanning, Claus ID Jensen, Finn V. Broenderslev ID DK Kjaerulff, Uffe DK Aalborg Pelletier, Paul A. Boise US Jensen, Lasse Rostrup Aalborg DK Parker, Marilyn A. Boise US Bogorad, Janice L. Allerod DK

US-CL-CURRENT: 706/46

L14: Entry 7 of 16 ·

Full 1	Title	Citation	Front	Review	Classification	Date	Reference	Sequences	Attachments	Claims	KWIC	Draw (
		_			91257 B1							

File: USPT

Record List Display Page 4 of 8

US-PAT-NO: 6591257

DOCUMENT-IDENTIFIER: US 6591257 B1

TITLE: Apparatus and method for a compositional decision support reasoning system

DATE-ISSUED: July 8, 2003

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY Martinka; Joseph J Sunnyvale CA Collins; Patricia Mountain View CA Forman; George H. Port Orchard WA Kirshenbaum; Evan R. Mountain View CA Seetharaman; Aparna Palo Alto CA

US-CL-CURRENT: 706/46

Full Title	Citation	Front	Review	Classification	Date	Reference	Section (Sec	Afternments.	Claims	KWIC	Drawi De

☐ 8. Document ID: US 6574537 B2

L14: Entry 8 of 16

File: USPT

Jun 3, 2003

US-PAT-NO: 6574537

DOCUMENT-IDENTIFIER: US 6574537 B2

TITLE: Diagnostic system and method

DATE-ISSUED: June 3, 2003

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY Kipersztok; Oscar Redmond WA Rein-Weston; Karl J. Seattle WA Nelson; Scott L. WA Issaquah Dildy; Glenn A. Sammamish WA Walker; Nicholas James Seattle WA Chew; Susan Chan Issaquah WA

US-CL-CURRENT: 701/29; 701/33, 701/34, 702/185, 714/25

Full	Title	Citation	Front	Review	Classification	Date	Reference	Secuences Stockheds Cla	ims KWIC	Draw, D

☐ 9. Document ID: US 6484010 B1

L14: Entry 9 of 16

File: USPT

Nov 19, 2002

US-PAT-NO: 6484010

DOCUMENT-IDENTIFIER: US 6484010 B1

** See image for Certificate of Correction **

Record List Display Page 5 of 8

TITLE: Tree-based approach to proficiency scaling and diagnostic assessment

DATE-ISSUED: November 19, 2002

INVENTOR-INFORMATION:

NAME

CITY

STATE ZIP CODE

COUNTRY

Sheehan; Kathleen M.

Skillman

NJ

US-CL-CURRENT: 434/362; 434/118, 434/322, 434/350

Full	Title Citation	Front Revie	w Classification	Date Reference	Saujerises: Alsoja ne rio	Claims KV	MC Draw De
	10. Docum	ent ID: US	6394952 B1				
т11.	Entry 10 of	F 16		File:	IISDT	May 28	2002

US-PAT-NO: 6394952

DOCUMENT-IDENTIFIER: US 6394952 B1

** See image for Certificate of Correction **

TITLE: Point of care diagnostic systems

DATE-ISSUED: May 28, 2002

INVENTOR-INFORMATION:

NAME	CITY	STATE	ZIP CODE COUNTRY
Anderson; Emory V.	Danville	CA	
Lapointe; Jerome	Oakland	CA	
Martinez; Ricardo	Santa Cruz	CA	
Marzolf; Gail	Cupertino	CA	
Pong; Ronald	San Jose	CA	
Jones; Lynn	Mountainview	CA	
Hussa; Robert O.	Sunnyvale	CA	
Nemec; Edward	Duluth	GA	
Senyei; Andrew E.	La Jolla	CA	
DeSieno; Duane	La Jolla	CA	

US-CL-CURRENT: 600/300; 435/4, 436/814, 600/304, 600/310, 600/351, 600/573, 600/584

Full	Title	Citation	Front	Review	Classification	Date	Reference	Sentences	-transments	Claims	KWC	Draw, De
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☐ 11. Document ID: US 6267722 B1

L14: Entry 11 of 16

File: USPT

Jul 31, 2001

US-PAT-NO: 6267722

DOCUMENT-IDENTIFIER: US 6267722 B1

** See image for Certificate of Correction **

Record List Display Page 6 of 8

TITLE: Point of care diagnostic systems

DATE-ISSUED: July 31, 2001

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Danville CA Anderson; Emory V. Nemec; Edward Duluth GΑ Lapointe; Jerome Oakland CA La Jolla CA DeSieno; Duane Martinez; Ricardo Santa Cruz CA CA Marzolf; Gail Cupertino Pong; Ronald San Jose CA

Jones; Lynn Mountain View CA
Hussa; Robert O. Sunnyvale CA

Senyei; Andrew E. La Jolla CA

US-CL-CURRENT: $\underline{600/300}$; $\underline{435/4}$, $\underline{436/811}$, $\underline{436/814}$, $\underline{600/304}$, $\underline{600/310}$, $\underline{600/345}$, $\underline{600/573}$, $\underline{600/584}$

Full Title Citation Front Review Classification Date Reference Sequences Attachnierts Claims KMC Draw De

☐ 12. Document ID: US 6219626 B1

L14: Entry 12 of 16

File: USPT

Apr 17, 2001

US-PAT-NO: 6219626

DOCUMENT-IDENTIFIER: US 6219626 B1

** See image for Certificate of Correction **

TITLE: Automated diagnostic system

DATE-ISSUED: April 17, 2001

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Steinmetz; Michael J. Kissimmee FL 34743 Kirst; Michael E. Kissimmee FL 34744

US-CL-CURRENT: 702/183; 702/182, 702/185, 714/25, 714/46

Full Title Citation Front Review Classification Date Reference Securities Attachments Claims KWC Draw. De

☐ 13. Document ID: US 6144838 A

L14: Entry 13 of 16 File: USPT Nov 7, 2000

US-PAT-NO: 6144838

DOCUMENT-IDENTIFIER: US 6144838 A

Record List Display Page 7 of 8

TITLE: Tree-based approach to proficiency scaling and diagnostic assessment

DATE-ISSUED: November 7, 2000

INVENTOR-INFORMATION:

NAME

CITY

STATE

ZIP CODE · COUNTRY

Sheehan; Kathleen M.

Skillman

NJ

US-CL-CURRENT: 434/362; 434/118, 434/322, 434/350

Draw, De

☑ 14. Document ID: US 6076083 A

L14: Entry 14 of 16

File: USPT

Jun 13, 2000

US-PAT-NO: 6076083

DOCUMENT-IDENTIFIER: US 6076083 A

TITLE: Diagnostic system utilizing a Bayesian network model having link weights

updated experimentally

DATE-ISSUED: June 13, 2000

INVENTOR-INFORMATION:

NAME

CITY

STATE

ZIP CODE

COUNTRY

Baker; Michelle

New York

NY

10025

US-CL-CURRENT: 706/52; 706/45, 706/46, 706/61

Full Title	Citation Front	Review	Classification	Date	Reference		1000	Claims	KWMC	Drawt De
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13.	Document IL); US 3	344300 A							
L14: Entry	15 of 16				File:	USPT		Aug	6,	1996

US-PAT-NO: 5544308

DOCUMENT-IDENTIFIER: US 5544308 A

TITLE: Method for automating the development and execution of diagnostic reasoning

software in products and processes

DATE-ISSUED: August 6, 1996

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY Giordano; Gerard J. Sparta NJ deMare; Gregory Sparta NJ Longendorfer; Betsy Ridgewood NJ Granieri; Michael N. Springfield VA

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Giordano; John P.

Sparta

NJ

Nolan; Mary E.

Lafayette

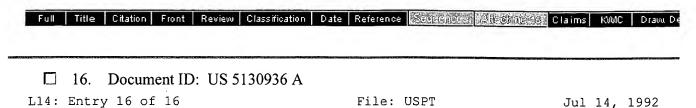
NJ

Levy; Ford

Pleasantville

NY

US-CL-CURRENT: <u>714/26</u>; <u>706/45</u>, <u>706/912</u>



US-PAT-NO: 5130936

DOCUMENT-IDENTIFIER: US 5130936 A

TITLE: Method and apparatus for diagnostic testing including a neural network for

determining testing sufficiency

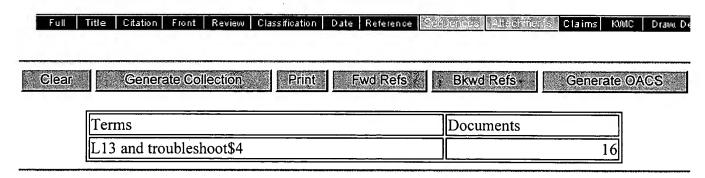
DATE-ISSUED: July 14, 1992

INVENTOR-INFORMATION:

NAME CITY STATE ZIP CODE COUNTRY

Sheppard; John W. Glen Burnie MD Simpson; William R. Edgewater MD Graham; Jerry L. Baldwin MD

US-CL-CURRENT: 702/123; 128/925, 324/73.1, 706/10, 706/20, 706/911



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[Abstract] [PDF Full-Text (524 KB)] **IEEE CNF**

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